





RELIABILITY DATA LT1106

8/21/2006

• OPERATING LIFE TEST

• OPERATING LIF	<u>E IESI</u>				
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SSOP/TSSOP	206 206	9413	9634	569.00 569.00	0 0
 HIGHLY ACCELI 	ERATED STRESS T	EST AT +131°C/85	%RH		
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICF HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
SSOP/TSSOP	304 304	9615	9727	626.42 626.42	0 0
 PRESSURE COC 	OKER TEST AT 15 P	PSIG, +121°C			
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SSOP/TSSOP	1,453 1,453	9421	9914	91.38 91.38	0 0
• TEMP CYCLE FF	ROM -65°C to +150°	С	•		
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SSOP/TSSOP	1,327 1,327	9421	9914	329.60 329.60	0 0
• THERMAL SHOO	CK FROM -65°C to	150°C			
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SSOP/TSSOP	770 770	9421	9914	197.13 197.13	0

- (1) Assumes Activation Energy = 1.0 Electron Volts
- (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 3.23 FITS
- (3) Mean Time Between Failures in Years = 35,318
- (4) Assumes 20X Acceleration from 85°C to +131°C

Note: 1 FIT = 1 Failure in One Billion Hours.

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